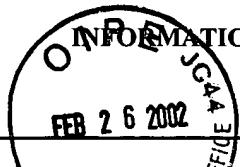


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INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 22, 1999

Group Art Unit: 2811

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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
Loke	5,254,208	10/19/1993	Zhang			
Loke	5,716,857	02/10/1998	Zhang			
Loke	6,008,078	12/28/1999	Zhang			

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Loke	02-140915	05/30/1990	JP			Full Eng
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↓	62-298151	12/25/1987	JP			Full Eng
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	02-153896	06/13/1990	JP			Eng Abst	
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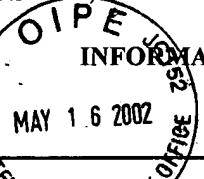
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